Digital synthesis for rad-hard components

Single Event Upsets mitigation techniques with TMRG tool



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Szymon KULIS, EP-ESE-ME, CERN

Agenda

- Radiation Effects
 - Single-event effects
 - Mitigation Techniques
- Triple Modular Redundancy Generator
 - Design flow
 - Triplicating the design (tmrg)
 - Physical implementation (plag)
 - Verification (tbg, seeg)
- Tools tips & tricks
- Summary

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Cumulative effects

Ionization Displacement (TID) (fluence)







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Single event effects

Triple Modular Redundancy Generator















TMRG



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Triple Modular Redundancy Generator

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time [seconds]

10-10

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Single Event Effects



Triple Modular Redundancy Generator

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TMRG



1) initial state : A=VDD, B=GND



SRAM cell (pass gates missing)

Triple Modular Redundancy Generator





initial state : A=VDD, B=GND
 charge deposited at drain of M1

SRAM cell (pass gates missing)

Triple Modular Redundancy Generator



1) initial state : A=VDD, B=GND

2) charge deposited at drain of M1

3) transient current changes temporary the state of node A (VDD-> GND)

SRAM cell (pass gates missing)

Triple Modular Redundancy Generator



1) initial state : A=VDD, B=GND

- 2) charge deposited at drain of M1
- 3) transient current changes temporary the state of node A (VDD-> GND)
- 4) before the desposited charge is evacuated, the second inverter (M3-M4) switches (node B GND->VDD)

SRAM cell (pass gates missing)



SRAM cell (pass gates missing) 1) initial state : A=VDD, B=GND

- 2) charge deposited at drain of M1
- 3) transient current changes temporary the state of node A (VDD-> GND)
- 4) before the desposited charge is evacuated, the second inverter (M3-M4) switches (node B GND->VDD)
- 5) The change of node B enforces the wrong state at node A -> the error is latched into the memory cell

How much charge is needed to flip the value?







Triple Modular Redundancy Generator





Amplitude of the current is increased until the upset is observed in simulation



SRAM cell (pass gates missing)

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Triple Modular Redundancy Generator





Triple Modular Redundancy Generator





SRAM cell (pass gates missing)

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SRAM cell (pass gates missing)

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SRAM cell (pass gates missing)

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SRAM cell (pass gates missing)

Triple Modular Redundancy Generator







Triple Modular Redundancy Generator

SEV and scaling



Scaling facts:

Supply Voltage Node

Capacitance

Critical energy

ENERGY (less charge needed to change the state)

Physical dimensions

SEU **CrOSS** section (less likely that particle hits the sensitive area)

Overall effect depends on circuit topology and radiation environment

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Technology level minimizing sensitive depth (like SOI)

Cell level

Increase the critical charge by increasing the node capacitance

-> larger transistors ("collection electrode" also gets bigger)

-> extra capacitance on metal layers



Technology level minimizing sensitive depth (like SOI)

Cell level

Increase the critical charge by increasing the node capacitance

> information stored in multiple nodes

DICE Whitaker SERT

Triple Modular Redundancy Generator





Technology level minimizing sensitive depth (like SOI)

Cell level

Increase the critical charge by increasing the node capacitance Triple Modular Encoding Redundancy (TMR)

System

level

redundancy

information stored in multiple nodes

Hamming

DICE Whitaker SERT

Reed – Solomon

Triple Modular Redundancy Generator



Doubled SRAM cell





* information is stored
in 4 nodes

"doubled" SRAM cell (pass gates missing)

Triple Modular Redundancy Generator

Doubled SRAM cell





Dual Interlocked Cell (DICE)



DICE cell (pass gates missing)

Triple Modular Redundancy Generator

Dual Interlocked Cell (DICE)





DICE cell (pass gates missing)

- # information is stored
 in 4 nodes (A,B,C,D)
- * two stable configurations (0,1,0,1) and (1,0,1,0)
- # data can propagate in two directions:
 - low level -> left
 - high level -> right
- no logic value can propagate for more than one stage in the same direction
- * drawbacks:
 - write requires access
 to two nodes
 - output glitch during SEV
 - rising clock during recovery time can latch the wrong value

Triple Modular Redundancy Generator



Dual Interlocked Cell (DICE)





Triple Modular Redundancy Generator

Hamming code example






Hamming code example





Data: 1 0 1 0 (tx) Message: 1 0 1 1 0 1 0 Hamming code example





Data: 1 0 1 0 (tx) Message: 1 0 1 1 0 1 0 (rx) Message: 1 0 1 1 0 0 0 s0 = p1@d1@d2@d4 = 0 s1 = p2@d1@d3@d4 = 1 s2 = p3@d2@d3@d4 = 1 err pos = [s2,s1,s0] = 6 -> d3

Hamming code example





Data: 1 0 1 0 (tx) Message: 1 0 1 1 0 1 0 (rx) Message: 1 0 1 1 0 0 0 s0 = p1@d1@d2@d4 = 0 s1 = p2@d1@d3@d4 = 1 s2 = p3@d2@d3@d4 = 1 err pos = [s2,s1,s0] = 6 -> d3

2" bits -> n+1 check bits

Triple Modular Redundancy (TMR) 🛦 TMRG

TMR is a technique based on
a majority voter cell
- (2n+1) inputs (usualy 3)
- 1 output equal to at least (n+1) inputs



Triple Modular Redundancy (TMR) 🛧 TMRG

Normaly, the three blocks give the same output



Triple Modular Redundancy (TMR) 🛧 TMRG

An upset in one block (e.g. B) is masked by the voter and is not seen at the output!





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TMRG

TMR: how NOT to triplicate FSM ATMRG



10 logic B logic C Starter Scotter Starter Scotter Starter Scotter Starter Scotter Starter Scotter Starter Starter Scotter Starter Sta

An error in flip-flop may never be corrected



TMRG

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TMRG

(ERN)





An error is removed from the system after one clock cylce

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Robust architecture



ΓMRG

Triple Modular Redundancy Generator

MRG

TMR: how to triplicate FSM (clock skew) 🛧 TMRG

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TMR: how to triplicate FSM (clock skew) 🛧 TMRG

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TMR: how to triplicate FSM (clock skew) 🛧 TMRG

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TMR Variants

		Triplicated Registers	Triplicated Registers + clock skew	Full TMR
Resoures (power, area)	FF	×3	×3	×3
	logic	×1	×1	×3
	voters	×1	×1	×3
	clocks	×1	×3	×3
Speed		+voter delay	+voter delay +clock skew	+voter delay
Protection				

Which one to use ?

Triple Modular Redundancy Generator

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TMR Variants – example 🗚 TMRG

* 8 Bit accumlator @ 100 MHz
* 65 nm CMOS technology, 9 track library, typical corner

	o <u>logic</u>	Togic Fast voter S	logic A voter for a G m logic B voter for a G m logic B voter for a G m logic C voter for a G m logic C voter for a G
	Not Triplicated	Triplicated Registers	Full TMR
Power [µW]	20.2	57.8 (×2.8)	111.9 (×5.5!)
Slack [ns]	8.01	7.5	7.63
Area [µm²]	130	348 (×2.6)	486 (×3.7)

*) estimations after synthesis

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TMR Variants – example 🗛 TMRG

* 8 Bit shift register @ 100 MHz
* 65 nm CMOS technology, 9 track library, typical corner

	œ <u>_</u> ₽]₽]₽]-@ œ_		voter filler (voter filler)
	Not Triplicated	Triplicated Registers	Full TMR
Power [µW]	9.2	26.1 (×2.8)	41.2 (×4.5!)
Area [µm²]	64	201 (×3.1)	288 (×4.5!)
Slack [ns]	9.67	9.17	9.28
fmax [GHz]	3.03	1.20 (39%)	1.38 (45%)
		∎ *) estimatio	ons after synthesis

TMR Variants – guidelines 🗛 TMRG

* Full TMR is recommended whenever possible

 In the case of limited resources (area, power):
 try to use full TMR or triplicated registers for state machines

* Always make sure that all states in the FSM are defined (default: nextState=reset;)

How to TMR the circuit ? **TMRG**

module inverter(input D, output ZN); assign ZN=!D; endmodule

Process: 1) copy & paste 2)add postfixes (A,B,C) module inverterTMR(
 input DA,
 input DB,
 input DC,
 output ZNA,
 output ZNB,
 output ZNC);
assign ZNA=!DA;
assign ZNB=!DA;
assign ZNC=!DC;
endmodule

How to TMR the circuit ? TMRG

module inverter(input D, output ZN); assign ZN=!D; endmodule

Process: 1) copy & paste 2)add postfixes (A,B,C) module inverterTMR(
 input DA,
 input DB,
 input DC,
 output ZNA,
 output ZNB,
 output ZNC);
assign ZNA=!DA;
assign ZNB=(DA;)
assign ZNC=!DC;
endmodule

Drawbacks of manual triplication: - time consuming

- error prone

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Triple Modular Redundancy Generator

Triple Modular Redundancy Generator

Triple Modular Redundancy Generator

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The purpose of the TMRG tool set is to automatize the process of triplicating digital circuits.

Requirements, the tool should:

- be compatible with the ASIC design flows used in the HEP community (Verilog RTL, Cadence tool chain)
- not over constraint the user's coding style (the source Verilog must be synthesizable)
- allow to obtain various flavors of TMR (registers only, full triplication, ...)
- assists in the physical implementation stage (synthesis, P&R)
- assists the designer in the verification process (generation of SEE)
- it can be run in batch mode (fully automatic flow)

TMRG : project status

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Setting started nstraining the design

Triple Modular Redundancy Generator

The TMRG tool is open source, however, it CAN NOT be made publicly available. By

describes the Triple Modular Redundancy Generator tool. The TMRG toolset assists in the

Before you start reading further, you should understand the purpose of the tool. The TMRG tool IS NOT a single button solution which will make your CHIP / FPGA design safe from single event upsets. You, as a designer, have to know which parts of your circuits should (have to) be protected. The TMRG tool will the top of the top protected for one of the top of the top of the top of the top. reading further, you should understand the purpose of the tool. The TMRG tool IS NOT ϵ

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signs immune to single event upsets. The immunity is provided by means of

Triple Modular Redundancy Generator

rocess of creating digital de

Ouick links

- Project started: Jan 2015
- Project size: >13000 lines of code
- Documentation size: 69 pages (pdf&html)
- Active user base: >7 designers

"Open source", hosted in CERN git repository (700+ commits)

Projects using TMRG

- **GBLD10+** 10 Gbps laser driver
 - **LDQ10** Quad array laser driver (4x10 Gbps)
- VLAD Quad array laser driver (4x10 Gbps)
- DRAD Digital radiation test chip
- **ePLL-CDR** PLL/CDR circuit macro block
- (relatively big) Chips to be submitted in following months
 - **IpGBT** 10 Gbps transceiver

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- MPA Macro Pixel ASIC for CMS tracker
- **SSA** Strip Senor ASIC for CMS tracker
 - SALT Silicon ASIC for LHCb Tracking

TMRG

Before starting ...

The TMRG tool IS NOT a single button solution which will make your CHIP design safe from single event upsets.

You, as a designer, have to know which parts of your circuits should (have to) be protected. The TMRG tool will save you the time needed for copy-pasting your code and will minimize probability that you will forget to change some postfix in your triplicated variable names. It will also simplify the physical implementation and verification process by providing some routines.

The TMRG is open source, however, it **CAN NOT** be made publicly available. The tool can be considered as **dual-use item** as it can be used to produce electronic circuits which are resistant to radiation.

If you find any problem with the tool chain please report it! Only by having your feedback we will be able to improve the tool chain!

Digital design flow

TMRG

Digital design flow

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Toolset:

- tmrg triplicates the Verilog code and generates synthesis constrains (for Design Compiler)
- tbg generates generic test bench template (with /without TMR, SEE injection, post synthesis, post PNR)
- plag generates placement directives (for Encounter)
- seeg generates Single Event Effects stimulus to be used for transient simulations

TMRG

triple modular redundancy generator

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Constraining the design

The TMRG tool:

- lets the designer decide which blocks and signals are to be triplicated by using TMRG directives (placed in Verilog code):
 - 1 // tmrg triplicate netName
 - 2 // tmrg do_not_triplicate netName
 - 3 // tmrg default [triplicate|do_not_triplicate]
- automatizes the "conversion" between triplicated and not triplicated signals:
 - if a non triplicated signal is connected to a triplicated signal a passive fanout is added
 - if a triplicated signal is connected to a non triplicated signal a majority voter is added

Signal source / Signal sink	non triplicated	triplicated
non triplicated	1 wire connection	fanout
triplicated	majority voter	3 wires connection *)
		*) see full TMR option later

TMRG Example1

Lets consider simple combinatorial module:



The module models an inverter, which contains only one input and one output.



TMRG

TMRG Example1: Triplicating everything A TMRG



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TMRG TMRG Example1: Logic and output triplication





TMRG Example1: Input and logic triplication TMRG



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TMRG Example1: Logic triplication





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TMRG Example1: Input and output triplication **TMRG**





TMRG Example: Summary





TMRG tool behavior can be controlled by TMRG constrains

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Majority voter, fanout ?



Some definitions:

common/voter.v

```
1 module majorityVoter (inA, inB, inC, out, tmrErr);
     parameter WIDTH = 1;
 2
    input [(WIDTH-1):0]
                            inA, inB, inC;
 3
    output [(WIDTH-1):0]
 4
                            out;
    output
                             tmrErr;
 5
                             tmrErr:
     reg
 6
    assign out = (inA&inB) | (inA&inC) | (inB&inC);
 7
     always @(inA or inB or inC)
 8
     begin
 9
      if (inA!=inB || inA!=inC || inB!=inC)
10
        tmrErr = 1;
11
       else
12
         tmrErr = 0;
13
14
     end
15 endmodule
```

common/fanout.v

1	module fa	anout (in, outA,	outB,	outC);		
2	<pre>parameter WIDTH = 1;</pre>					
3	input	[(WIDTH-1):0]	in;			
4	output	[(WIDTH-1):0]	outA	,outB,outC;		
5	assign	outA=in;				
6	assign	outB=in;				
7	assign	outC=in;				
8	endmodul	e				

If needed this definitions are added to the output file, can also be replaced by user defined modules.



FSM Example: triplication without voting





If an error occurs in one branch, it will propagate along the branch. If there is no repair mechanism, after the first error the effective cross section is doubled with respect to the non triplicated circuit. In order to eliminate this problem, a voted feedback is needed!

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FSM Example: triplicating only the register



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TMRG

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FSM Example: triplicating the register and clock skew



TMRG

Introducing full TMR



To generate **full TMR (3 interconnected majority voters)** a net declaration with a specific name (**Voted** postfix) has to be used:

```
1 wire netVoted = net;
```

This syntax ensures that non triplicated Verilog code can be simulated and/or synthesized.



Full TMR: Voting triplicated signals





Full TMR: logic triplication and voting





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FSM Example: triplication and voting



Triple Modular Redundancy Generator



General concepts related to module instantiation triplication:

- Only named connections are supported for module instantiation!
- All modules must be known at the time of triplication.
- If a module is not be triplicated internally (e.g. library cell, analog macro cell) one has to add directive do_not_touch in the module body.
- For all other modules (not from library and not having do_not_touch constrain):
 - triplication is always done inside the module,
 - a new (triplicated) module has a TMR postfix appended to the name,
 - I/O names may change.

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Triplicating a fixed macro cell





Triple Modular Redundancy Generator

Not triplicating a fixed macro cell





Triple Modular Redundancy Generator

Triplicating user's modules





When the module being instantiated is a subject of triplication, only connections are modified and voters and fanouts are added if necessary.

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41);

42 endmodule

.ZNC(outC)



Triplication brings new features - tmrError

- It may be desirable to know if one of the triplicated signals is different from the other two (whether an single event upset has happened or not)
- The TMRG tool always generates:
 - **tmrError** output associated with each voter. .inA(memA), 2 .inB(memB), 3 For a signal mem the voter can look like: .inC(memC), 4 Combination (OR) of all error signals .out(mem), 5 .tmrErr(memTmrError) 6 inside given module); 7 assign tmrErrorC = dff01tmrErrorC|dff02tmrErrorC|in3TmrErrorC;
- To make use of the signal (particular or global) it is enough to make a declaration:

```
1 wire memTmrError=1'b0;
2 wire tmrError=1'b0;
```

This definition will be removed by the TMRG tool and the wire will be connected directly to the error output of the voter. By declaring tmrError the designer gains access to the signal and can implement the required functionality. Moreover, assigning zero value ensures that the non triplicated circuit is not affected and can be simulated.

• If user does not use the tmrError functionality it will be optimized out by the synthesizer



TMRG

1 majorityVoter memVoter (

tmrError Example





TmrError can be used to implement SEU counter!

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....

37 assign tmrError = memTmrError;

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- Accessing individual signals from a triplicated bus (e.g. power on reset monitoring)
- Generating a triplicated bus from other signals (e.g. clock gating for production testing)
- Generating identical slices of logic (timing critical logic) (e.g. feedback divider for PLL)
- Specify majority voter and fanout cells on per module basis (e.g. different voter for clock multiplexer)
- Integrated with SVN / CLIOSOFT sos version control systems

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How to constrains the design ?



Constrains do not have to be places in the source code directly. Constrains can be

- loaded from a configuration file
 - The configuration file uses standard INI file format. It is a simple text file with a basic structure composed of sections, properties, and values. An example file may look like:

[modName]
 default : triplicate
 net : triplicate
 net : do_not_triplicate
 tmr_error : true

- To load a configuration file, you have to specify its name as a command line argument:

```
$ tmrg -c config.cfg [other_options]
```

- \$ tmrg --config config.cfg [other_options]
- **provided as a command line arguments**. This approach is not very effective for constraining the whole project, but may be really handy in the initial phase. A possible constrains are shown bellow:

```
$ tmrg -d "default triplicate modName" [other_options]
$ tmrg -d "triplicate modName.net" [other_options]
$ tmrg -d "do_not_triplicate modName.net" [other_options]
$ tmrg -d "tmr_error true modName" [other_options]
```





Most of the code generated by TMRG tool is redundant → synthesizer will want to remove it (undesirable behavior!)

The TMRG generates a set of constrains for you which will force Design Compiler not to discard the redundant logic:

\$ tmrg --generate_sdc --sdc_headers comb06.v

As a result, a file comb06TMR.sdc will be generated. The file is a SDC file which can be loaded from the RC.

set sdc_version 1.3
set_dont_touch /designs/comb06TMR/nets/combLogicA
set_dont_touch /designs/comb06TMR/nets/combLogicB
set_dont_touch /designs/comb06TMR/nets/combLogicC
set_dont_touch /designs/comb06TMR/nets/inA
set_dont_touch /designs/comb06TMR/nets/inB
set_dont_touch /designs/comb06TMR/nets/inC
set_dont_touch /designs/comb06TMR/nets/in





RTL Compiler / Genus tips & tricks



Problem: how to make sure that the synthesis tool does not remove a specific cell?

Example Verilog code:

```
[..]
INVD1 instName(.I(myInput), .ZN(myOutput));
[..]
```

SDC constrain file:

set_dont_touch INVD1

Any of INVD1 instances will not be touched!

RC/Genus script:

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set_attribute preserve true /path/instName

Specific instance will be preserved!





- Small projects/files the TMRG tool should be usually very fast. As the TMRG does not invoke
 a complex runtime environment, the execution time should be well below 1s
- Medium / large chip (in HEP community):

Chip	Die size [mm^2]	RTL Lines	TMR RTL Lines	TMRG run time [s]	Synthesis time [s]
lpGBT	4.5x4.5	36368	55776	173.3	T.B.D.
MPA	12x25	8937	21617	42.1	9000
SSA	11x4.5	3708	9081	20	6945
SALT	4x11	11612	20447	61.6	T.B.D.

*) The RTL lines count and die size are given only to indicate the chip size and complexity level.



PLAG



placement generator



Triple Modular Redundancy Generator



Placement Generator

- TMRG
- Majority voters before (or after) flip-flops cause the P&R tool to place instances of triplicated flip-flops close together (in order to keep the routing short).
- Multiple bit upsets can lead to malfunctioning of the triplicated design:
 - → one has to ensure that the triplicated instances of the same element are placed far from each each other.
- The **PLAG** tool:

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- can assign registers (or other type of cells) to a specific Instances Group. A minimum distance is enforced, while leaving Encounter freedom to optimize the placement,
- operates on a final netlist.



PLAG: Example





TMRG

PLAG: Example





Triple Modular Redundancy Generator

Innovus tips & tricks



Similar behaviour can be obtained with the newest version of Innovus P&N tool using command:

```
create_inst_space_group groupName
    -inst listOfInstances
    -spacing <value>
```

Creates space group for instances with a specific vertical-distance constraint. -inst listOfInstances - specifies all instances that belong to the same space group by name. -spacing verticalDistance - specifies the vertical distance, in microns, between each specific instance.

SEEG



single event effects generator



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SEE simulation



Once the design is implemented one should **verify** that the design still works as intended and that the design in **immune to SEE**.

How can we inject errors?

• Verilog:

force name=value;

release name;

• System Verilog:

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\$deposit(name, value);



Single Event Effects Generator

SEEG tool streamlines the verification process.

An example usage of the tool for the netlist generated for an example fsm02 can look like:

seeg --lib libs/tcbn65lp.v --output see.v r2g.v

The SEEG generates a file (see.v) which contains several verilog tasks, which can toggle nets (to simulate SET) or toggle flip-flops state (to simulate SEU) or both:



The approach has been verified with 65nm-HEP CMOS standard cell library and with custom standard cell library characterized with Liberate (lpGbtxHsLib).

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Single Event Effects Generator

Example usage of SEEG generated tasks:

- Randomize :
 - the delay until next event
 - the length of the next event —
 - Randomize the node (wire) to be affected (see / seu / set)
- Activate "upset" (force)
- Deactivate upset (release)

This is only a template which may be used as a starting point.

module stimulus:

```
fsm02TMR_DUT(...):
```

[...]

integer	SEEEnable=1;	11	enables SEE generator
integer	<pre>SEEnextTime;</pre>	11	time until the next SEE event
integer	SEEduration;	11	duration of the next SEE event
integer	SEEwireId;	11	wire to be affected by the next SEE event
integer	SEEmaxWireId;	11	number of wires in the design which can be affected by SEE event
integer	<pre>MAX_UPSET_TIME=10;</pre>	11	10 ns (change if you are using different timescale)
integer	SEEDel=100;	11	100 ns (change if you are using different timescale)
integer	SEECounter;	11	number of simulated SEE events
reg	<pre>SEEActive=0;</pre>	11	high during any SEE event

// get number of wires

initial see max net (SEEmaxWireId);

include "fsm02TMR see.v"

alwavs

end

begin if (SEEEnable)

begin

// randomize time, duration, and wire of the next SEE SEEnextTime = SEEDel/2 {\$random} % SEEDel;

SEEduration = {\$random} % (MAX_UPSET_TIME-1) + 1; // SEE time is from 1 - MAX_UPSET_TIME SEEwireId = {\$random} % SEEmaxWireId;

// wait for SEE

#(SEEnextTime);

// SEE happens here! Toggle the selected wire. SEECounter=SEECounter+1; SEEActive=1; see force net(SEEwireId); see display net(SEEwireId); // probably you want to comment this line ? #(SEEduration): see release net(SEEwireId); SEEActive=0; end else #10: endmodule



TMRG

SEEG - example





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TBG



test bench generator



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Test Bench Generator



// fanout for clk

wire clkA=clk; wire clkB=clk:

wire clkC=clk;
// fanout for in

wire inA=in:

wire inB=in:

wire inC=in;
// voter for out

wire outA:

wire outB;

wire outC;
wire outtmrErr;

.inA(outA),

.inB(outB),
.inC(outC),

.out(out),

fsm02TMR DUT (

.clkA(clkA),

.clkB(clkB),

.clkC(clkC),

.inA(inA),

.inB(inB),

.inC(inC),

.outA(outA), .outB(outB),

.outC(outC)

fsm02 DUT (
 .clk(clk),

.in(in),
.out(out)

);

);

`else

);

endif

majoritvVoterTB outVote

.tmrErr(outtmrErr)

`ifdef TMR

TBG generates a generic test bench

- RTL description / Netlist
- Non triplicated / triplicated version
 (automatic fanout/majority voter insertion for inputs/outputs)
- SDF timing annotation

```
`ifdef SDF
    initial
    $sdf_annotate("r2g.sdf", DUT, ,"sdf.log", "MAXIMUM");
    `endif
```

• SET/SEU/SEE generation

```
`ifdef SEE
                                // enables SEE generator
         SEEEnable=0:
 гед
                                // high during any SEE event
         SEEActive=0:
 гед
                                // time until the next SEE event
 integer SEEnextTime=0;
 integer SEEduration=0;
                                // duration of the next SEE event
 integer SEEwireId=0;
                                // wire to be affected by the next SEE event
 integer SEEmaxWireId=0;
                                // number of wires in the design which can be af
 integer SEEmaxUpaseTime=1000; // 1 ns (change if you are using different time
 integer SEEDel=100 000;
                                // 100 ns (change if you are using different tim
 integer SEECounter=0;
                                // number of simulated SEE events
 `include "see.v"
                                // include tasks generated by seeg
 [..]
`endif
```

- simple clock/reset generators
- # tbg topModule.v -o topModule_test.v





DEMO



DEMO



source tmrg/etc/tmrg.sh

```
# tmrg --help
Usage: tmrg [options] fileName
```

```
Options:
```

```
--version show program's version number and exit
-h, --help show this help message and exit
-v, --verbose More verbose output (use: -v, -vv, -vvv..)
--doc Open documentation in web browser
```

```
[...]
```

```
TMRG toolset:
```

```
tmrg - Triple Modular Redundancy Generator
  (triplicates verilog netlist)
seeg - Single Event Effects Generator
  (helps in the verification of triplicated netlist)
plag - Placement Generator
  (helps with placement of triplicated circuit)
tbg - Testbench Generator
  (creates template for the testbench)
```



DFF example | RTL





DFF example | Verbose

tmrg -v counter.v

Going verbose "-v" | Loading file 'counter.v' [INFO **[INFO** [INFO Elaborating counter.v [INFO Module counter (counter.v) **[INFO** Port mode : ANSI [INFO [INFO Checking the design hierarchy **[INFO** [counter] [INFO **[INFO** Applving constrains [INFO 1 Module counter [INFO tmrErrOut : False (configGlobal:False) net rst : True (configGlobalDefault:True) [INFO net g : True (configGlobalDefault:True) [INFO **[INFO** net clk40M : True (configGlobalDefault:True) net d : True (configGlobalDefault:True) **[INFO** [INFO **[INFO** Applying constrains by name [INFO Module counter [INFO [INFO Module:counter [INFO **[INFO** Nets tmr range **[INFO** [INFO rst True [INFO True [7:0] a [INFO clk40M True [INFO True d [INFO Triplciation starts here [INFO Going even more [INFO [INFO] Triplicating file counter.v verbose "-vv"] Generating SDC constraints file ./counterTMR.sdc [INFO



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DFF example | Triplication



DFF example | Place

plag --lib /homedir/skulis/tmrg/trunk/libs/tcbn65lp.v \
 dffTMR_rc/r2g.v

cat tmrPlace.tcl

addInstToInstGroup tmrGroupA {dffTMR/qA_reg} addInstToInstGroup tmrGroupB {dffTMR/qB_reg} addInstToInstGroup tmrGroupC {dffTMR/qC_reg}

In the encounter flow:

```
[..]
createInstGroup tmrGroupA -region 0 0 10 10
createInstGroup tmrGroupB -region 10 0 20 10
createInstGroup tmrGroupB -region 20 0 30 10
source tmrPlace.tcl
[..]
```



output



DFF example | Verification

seeg --lib /homedir/skulis/tmrg/trunk/libs/tcbn65lp.v

r2g.v

cat see.v

task set_force_net; input wireid; integer wireid; begin case (wireid) 0 : force DUT 1 : force DUT



use -v for verbose output

0 : force DUT.qC_reg.Q = ~DUT.qC_reg.Q; 1 : force DUT.dVoterA.Fp9999955A.ZN = ~DUT.dVoterA.Fp9999955A.ZN; 2 : force DUT.dVoterA.p214748365A.ZN = ~DUT.dVoterA.p214748365A.ZN; 3 : force DUT.dVoterC.Fp9999955A.ZN = ~DUT.dVoterC.Fp9999955A.ZN; 4 : force DUT.dVoterC.p214748365A.ZN = ~DUT.dVoterC.p214748365A.ZN; 5 : force DUT.dVoterB.Fp9999955A.ZN = ~DUT.dVoterB.Fp9999955A.ZN; 6 : force DUT.dVoterB.p214748365A.ZN = ~DUT.dVoterB.Fp9999955A.ZN; 7 : force DUT.dVoterB.p214748365A.ZN = ~DUT.dVoterB.p214748365A.ZN; 8 : force DUT.qB_reg.Q = ~DUT.qB_reg.Q; 8 : force DUT.qA_reg.Q = ~DUT.qA_reg.Q; endcase end endtask task set_release_net; task set_display_net;

task set_display_net; task set_max_net;

task seu_force_net; task seu_release_net; task seu_display_net; task seu_max_net;

task see_force_net; task see_release_net; task see_display_net; task see_max_net;



et; SEE et;

DFF example | Verification

tbg counter.v -o counter_test.v # cat counter_test.v

```
`timescale 1 ps / 1 ps
[..]
module counter_test;
```

// Input/Output section
 reg clk;
 wire [7:0] q;
 reg rst;

// Device Under Test section

```
`ifdef TMR
  [...]
  counterTMR DUT (
    .clkA(clkA),
    .clkB(clkB),
    .clkC(clkC),
    .qA(qA),
    .qB(qB),
    .qC(qC),
    .rstA(rstA),
    .rstB(rstB),
    .rstC(rstC)
  );
`else
  counter DUT (
    .clk(clk),
    .q(q),
    .rst(rst)
  );
`endif
```

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Triple Modular Redundancy Generator

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DEMO Summary

Conclusions:

- TMRG tool chain is **easy to use**
- TMRG flow can be **fully automatized**
- TMRG tool should be used with caution



Current Limitations



- The TMRG supports only a subset of the Verilog language (sophisticated constructions may lead to incorrect results).
- The tool is not able to handle all possible coding styles:
 - Concatenation of triplicated and not triplicated variables on the left hand side of an assignment
 - unnamed connections for the module instantiation
- System Verilog syntax is not supported
- Parser error messages are not very verbose
- Some constants are hard-coded in the source code (like A,B,C postfixes for triplicated signals names)
- Higher order replication (5, 7, 9, ...) is not supported

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Still maturing but a very useful tool!

L			
_	-		

```
2 localparam k=8;
                                                    3 wor dataTmrError;
                                                    4 wire [k-1:0] data [ 2*k-1 : 0 ] ;
                                                    5 wor selTmrError:
                                                    6 wire [2:0] sel:
                                                    7 reg [2:0] selA;
                                                    8 reg [2:0] selB;
                                                    9 reg [2:0] selC;
                                                   10 reg [k-1:0] dataA [ 2*k-1 : 0 ] ;
                                                   11 reg [k-1:0] dataB [ 2*k-1 : 0 ] ;
                                                   12 reg [k-1:0] dataC [ 2*k-1 : 0 ] ;
                                                   13 wire [k-1:0] dataMux = data[sel] ;
                                                   14
2 localparam k=8;
                                                   15 majorityVoter #(.WIDTH(3)) selVoter (
                                                   16
                                                          .inA(selA),
3 // tmrg do not triplicate dataMux
                                                   17
                                                          .inB(selB),
                                                          .inC(selC),
                                                   18
5 reg [k-1:0] data [2*k-1:0];
                                                   19
                                                          .out(sel),
                                                          .tmrErr(selTmrError)
                                                   20
6 wire [k-1:0] dataMux = data[sel];
                                                   21
                                                          );
                                                   22
                                                   23 genvar gen dataVoter;
                                                   24 generate
                                                        for(gen_dataVoter = ((0>2*k-1) ? 2*k-1 : 0);gen_dataVoter<((0>2*k-1) ? 0 : 2*k-1);gen_dataVoter = gen_dataVoter+1)
                                                   25
                                                          begin : gen dataVoter fanout
                                                   26
                                                   27
                                                   28
                                                            majorityVoter #(.WIDTH(((k-1)>(0)) ? ((k-1)-(0)+1) : ((0)-(k-1)+1))) dataVoter (
                                                   29
                                                                .inA(dataA[gen_dataVoter] ),
                                                                .inB(dataB[gen_dataVoter] ),
                                                   30
                                                                .inC(dataC[gen dataVoter] ),
                                                   31
                                                   32
                                                                .out(data[gen dataVoter] ),
                                                   33
                                                                .tmrErr(dataTmrError)
                                                   34
                                                                );
                                                   35
                                                          end
                                                   36 endgenerate
                                                   37 [...]
```

Triple Modular Redundancy Generator

TMRG

CERN

1[...]

7 [...]

4 reg [2:0] sel;

Summary



Single Event Effects mitigation techniques:

- Technology level (minimizing sensitivity depth)
- Cell level (increasing critical charge, information stored on multiple nodes)
- System level:
 - Encoding (Hamming, Reed Solomon, ...)
 - Triple Modular Redundancy
 - Registers only
 - Registers and clocks
 - Full triplication



Summary



- TMRG tool chain assists user along the design process of electronics resistant to Single Event Effects
 - It is compatible with the typical ASIC design flows used in the HEP community
 - It does not over constraint the user's coding style
 - It allows to obtain various flavors of TMR (registers only, full triplication, ...)
 - it assists in the physical implementation stage (synthesis, P&R)
 - It assists in the verification process (generation of SEE)
 - It can be run in batch mode (fully automatic flow)
- To get started check the documentation at : cern.ch/tmrg
- **Development still continues, your feedback is essential!**



Thank you very much for your attention!



- questions ?
- suggestions ?
 - remarks ?
 - requests ?

Please visit : cern.ch/tmrg

Further reading



- Single event effects in static and dynamic registers in a 0.25 µm CMOS technology F. Faccio; K. Kloukinas; A. Marchioro; T. Calin; J. Cosculluela; M. Nicolaidis; R. Velazco IEEE Transactions on Nuclear Science, Year: 1999, Volume: 46, Issue: 6
- An SEU-Robust Configurable Logic Block for the Implementation of a Radiation-Tolerant FPGA S. Bonacini; F. Faccio; K. Kloukinas; A. Marchioro IEEE Transactions on Nuclear Science, Year: 2006, Volume: 53, Issue: 6
- Computational method to estimate Single Event Upset rates in an accelerator environment *M Huhtinen and F Faccio NIMA, Year: 2000, Volume:450, Issue:1*
- Characterization of a commercial 65 nm CMOS technology for SLHC applications S Bonacini, P Valerio, R Avramidou, R Ballabriga, F Faccio, K Kloukinas and A Marchioro Journal of Instrumentation, Volume 7, January 2012
- Single-event upset sensitivity of latches in a 90nm dual and triple well CMOS technology L Pierobon, S Bonacini, F Faccio and A Marchioro Journal of Instrumentation, Volume 6, December 2011
- Design and characterization of an SEU-robust register in 130nm CMOS for application in HEP ASICs S Bonaci Journal of Instrumentation, Volume 5, November 2010





Backup slides



Single Event Effects



Single-event effect (SEE) is a phenomena triggered by a charged particle passing through an electronic device. Traversing particle ionizes the matter producing electron-holes pairs. The amount of charge being generated depends on particle type, particle energy, incident angle, material. The charge can be then collected by a drain/source diffusion and can modify its voltage, changing its logical value (from zero to one or vice versa).

Traditionally we distinguish two types of upsets:

- **Single-event transient (SET)** is a phenomena in which an error happens in a combinatorial logic. It appears as a short glitch on a net. The proper value is restored within short time (~ns). Importance of SET increases with increasing clock frequency when the duration of SET becomes comparable with a clock period.
- **Single-event upsets (SEU)** are errors induced in memory cells (like flip-flop). In contradiction to SET, the value of the memory cell does not recover after SEU.





Tripple Module Redundancy

There have been several techniques proposed in order to protect the circuit against events caused by the ionizing particles. Virtually all techniques relay on a **data redundancy**. It is assumed, that if the bit of information is stored in several places (nodes) the information can be properly reconstructed even if some of these places (nodes) get disturbed. There are some circuit techniques, based on **hardening standard cells** while the other techniques address the problem at the **system level**, by utilizing error-correcting coding (ECC), temporal redundancy, or Tripple Module Redundancy.

Tripple Module Redundancy (TMR) concept was originally developed by Von Neumann, with the main purpose of enhancing reliability of electronic circuits. This concept was later applied in microelectronics for protection against ionizing particles.

The purpose of TMRG tool is to automatize process of triplicating digital circuits.



Accessing individual signals from a triplicated bus ACCESSING TARG

In some very spetial cases you may want to access signals after the triplication individually. Imagine that you are designing a reset circuit. You want to have a

- Power-on reset (POR) block
- and an external reset signal.

As you do not want that SET in POR block resets your chip, you may decide to triplicate the block. For practical reasons, you still want to keep only one external reset pin.



TMRG

1	module powerOnReset(
2	z
3);
4	output z;
5	endmodule
6	<pre>module resetBlock01TMR(</pre>
7	rstn,
8	rstA,
9	rstB,
10	rstC
11);
12	wire rstnC;
13	wire rstnB;
14	wire rstnA;
15	<pre>input rstn;</pre>
16	output rstA;
17	output rstB;
18	output rstC;
19	wire porRstA;
20	wire porRstB;
21	wire porRstC;
22	assign rstA = !rstnA porRst
23	assign rstB = !rstnB porRst
24	<pre>assign rstC = !rstnC porRst</pre>
25	
26	powerOnReset porA (
27	.z(porRstA)
28);
29	
30	powerOnReset porB (
31	.z(porRstB)
32);
33	
34	powerOnReset porC (
35	.z(porRstC)
36);
37	
38	fanout rstnFanout (
39	.in(rstn),
40	.outA(rstnA),
41	.outB(rstnB),
42	.outc(rstnc)
43); andradula
44	enamodulle

There is not magic so far.

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Triple Modular Redundancy Generator

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Accessing individual signals from a triplicated bus ACCESSING TARG

If you decided that you would like to able to check during normal operation what is the status of the POR output, the straight forward way of doing that would be:

```
1 module powerOnReset(z);
  // tmrg do not touch
2
3
    output z;
4 endmodule
5
6 module resetBlock (rstn,rst,porStatus);
   // tmrg do not triplicate rstn
7
    input rstn;
8
    output rst;
9
    output porStatus;
10
    wire porRst;
11
    assign porStatus=porRst;
12
    assign rst=!rstn | porRst;
13
    powerOnReset por(.z(porRst));
14
15 endmodule
```

You may see that 'porStatus' signal got triplicated which is of course what we want. Lets think if this is what you really want. If you connect it to some kind of digital bus, most likely you will have some voting on the way, so you will not have an information about individual signals.



-	moduce poweronnesee(
2	Z
3);
4	output z;
5	endmodule
6	<pre>module resetBlockTMR(</pre>
7	rstn,
8	rstA,
9	rstB,
10	rstC,
11	porStatusA,
12	porStatusB,
13	porStatusC
14);
15	wire rstnC;
16	wire rstnB;
17	wire rstnA;
18	input rstn;
19	output rstA;
20	output rstB;
21	output rstC;
22	output porStatusA;
23	output porStatusB;
24	output porStatusC;
25	wire porRstA;
26	wire porRstB;
27	wire porkst(;
28	assign porStatusA = porRstA;
29	assign porStatusB = porRstB;
20	assign porstatuse = porkste;
32	assign rstR = irstnR porRstR;
32	assign rstC = irstnCiporRstC;
34	assign race - tracheportate,
35	nowerOnReset norA (
36	z(porRstA)
37):
38	
39	powerOnReset porB (
40	.z(porRstB)
41);
42	
43	powerOnReset porC (
44	.z(porRstC)
45);
46	
47	fanout rstnFanout (
48	.in(rstn),
49	.outA(rstnA),
50	.outB(rstnB),
51	.outC(rstnC)
52);
53	endmodul e

1 madula novor0nPoroti



A brief summary of all constrains, ways of specifying it, and priorities is shown in Table below.

directive in code (lowest priority)	configuration file (medium priority)	command line argument (highest priority)	
<pre>module modName();</pre>	[modName]	-	
<pre>// tmrg default triplicate</pre>	default : triplicate	-d "default triplicate modName"	
<pre>// tmrg triplicate net</pre>	net : triplicate	<pre>-d "triplicate modName.net"</pre>	
<pre>// tmrg do_not_triplicate net</pre>	<pre>net : do_not_triplicate</pre>	<pre>-d "do_not_triplicate modName.net"</pre>	
<pre>// tmrg tmr_error true</pre>	tmr_error : true	- d "tmr_error true modName"	
<pre>// tmrg tmr_error_exclude net</pre>	<pre>tmr_error_exclude : net</pre>	<pre>-d "tmr_error_exclude modName.net"</pre>	
// tmrg slicing	slicing : net	- d "slicing modName"	
<pre>// tmrg majority_voter_cell name</pre>	<pre>majority_voter_cell : name</pre>	<pre>-d "majority_voter_cell name modName"</pre>	
<pre>// tmrg fanout_cell name</pre>	<pre>fanout_cell : name</pre>	- d "fanout_cell name modName"	

Triple Modular Redundancy Generator



As there are several ways of specifying constrains and one constrain can be overwritten by another, there is mechanism which can ensure the designer that all his intentions are interpreted properly.

Lets consider the comb06 module from the above example. Lets write a configuration files comb06.cnf:

[comb06] default : do_not_triplicate in : triplicate out : do_not_triplicate combLogic : triplicate tmr_error : true

When you run TMRG with additional options and constrains as shown below:

```
$ tmrg -vv \
    -w "default triplicate comb06" \
    -w "tmr_error false comb06" \
    -w "triplicate comb06.combLogic" \
    -c comb06.cnf \
    comb06.v
```



How to constrains the design (debugging) ?



ERN

The **detailed log** of what is being done can be generated (-v option)

The table at the end of the listing summarizes all discovered signals and applied constrains.

Step by step process of applying constrains can be used to understand at which point something went wrong:

- Used configuration files
- Command line constrains
- Constrains evaluation for given nets

[..] [DEBUG Loading master config file from /home/skulis/work/tmrg/trunk/bin/../etc/tmrg.cfg [DEBUG Loading user config file from /home/skulis/.tmrg.cfg Loading command line specified config file from comb06.cnf DEBUG ...1 [INFO Command line constrain 'directive default' for module 'comb06' (value:True) [INFO Command line constrain 'directive tmr error' for module 'comb06' (value:False) [INFO Command line constrain 'directive triplicate' for net 'combLogic' in module 'comb06' [..] [INFO Applying constrains [INFO 1 Module comb06 [INFO tmrErrOut : False (configGlobal:False -> configModule:True -> cmdModule:False) | net combLogic : True (configGlobalDefault:True [INFO -> srcModuleDefault:True -> configModuleDefault:False -> cmdModuleDefault:True -> src:False -> config:True -> cmd:True) INFO net in : True (configGlobalDefault:True -> srcModuleDefault:True -> configModuleDefault:False -> cmdModuleDefault:True -> config:True) | net out : False (configGlobalDefault:True [INFO -> srcModuleDefault:True -> configModuleDefault:False -> cmdModuleDefault:True -> config:False) [..] Summarv [INFO Module:comb06 [INFO [INFO Nets tm [INFO [INFO] | combLogic True] | in [INFO True [INFO 1 | out False [INFO [..]

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Triple Modular Redundancy Generator

Accessing individual signals from a triplicated bus ACCESSING TMRG

In order to solve the problem, you have to "code" some triplication manually. If you

declare a wire with a special name and with a special assignment (like bellow) you 3); 4 output z; gain access to the signal after triplication: 5 endmodule 6 module resetBlockTMR(7 rstn, rstA, 9 rstB. 1 wire myWire; 10 rstC. porStatusA, 11 2 wire myWireA=myWire; 12 porStatusB, 13 porStatusC 14): 3 wire myWireB=myWire; 15 wire rstnC; 16 wire rstnB; 4 wire myWireC=myWire; 17 wire rstnA; 18 input rstn: 19 output rstA: This convention ensures that you can still simulate and synthesize you original 20 output rstB: 21 output rstC; 22 output [2:0] porStatusA; design. TMRG will convert this declarations during elaboration process to the desired 23 output [2:0] porStatusB; 24 output [2:0] porStatusC; ones. Lets see how we can use this in our resetBlock example. 25 wire porRstA; 26 wire porRstB; 27 wire porRstC: 1 module powerOnReset(z); 28 assign porStatusA = {porRstC,porRstB,porRstA}; 2 // tmrg do not touch 29 assign porStatusB = {porRstC,porRstB,porRstA}; 3 output z; 30 assign porStatusC = {porRstC,porRstB,porRstA}; 31 assign rstA = !rstnA|porRstA; 4 endmodule 32 assign rstB = !rstnB|porRstB; 5 33 assign rstC = !rstnC|porRstC; 34 6 module resetBlock (rstn,rst,porStatus); 35 powerOnReset porA (// tmrg do not triplicate rstn 7 36 .z(porRstA) <u>TMRG</u> 37); 8 input rstn; 38 9 output rst; 39 powerOnReset porB (vector! output [2:0] porStatus; 10 40 .z(porRstB) 41); 11 wire porRst; 42 12 wire porRstA=porRst; 43 powerOnReset porC (wire porRstB=porRst; 13 44 .z(porRstC) 45); 14 wire porRstC=porRst; 46 15 assign porStatus={porRstC,porRstB,porRstA}; 47 fanout rstnFanout (48 .in(rstn), 16 assign rst=!rstn | porRst; 49 .outA(rstnA), 17 powerOnReset por(.z(porRst)); .outB(rstnB), 50 18 endmodule 51 .outC(rstnC) 52); As you can see, we ended up with triplicated bus (9 signals!). 53 endmodule

```
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```

Triple Modular Redundancy Generator

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1 module powerOnReset(

2 z

Accessing individual signals from a triplicated bus ACCESSING INDIVIDUAL

In the previous example it was shown how to fanout a signal in order to access sub-signals in a triplicated signal. Now let us consider opposite situation, how to generate triplicated signal from arbitrary combination of other signals.

To make example easier to understand, lets take real-life problem: we want to make a clock gating circuit. A simple implementation with only one gating signal may look like:

1	module	clockGating	<pre>(clkIn,clkOut,clkGate);</pre>
---	--------	-------------	------------------------------------

```
2 // tmrg default triplicate
```

- 3 input clkIn;
- 4 output clkOut;
- 5 input clkGate;
- 6 assign clkOut=clkIn&clkGate;
- 7 endmodule

No magic so far.



1 module clockGatingTMR(

- 2 clkInA,
- 3 clkInB,
- 4 clkInC,
- 5 clkOutA,
- 6 clkOutB,
- 7 clkOutC,
- 8 clkGateA,
- 9 clkGateB,
- 10 clkGateC
- 11);
- 12 input clkInA;
- 13 input clkInB;
- 14 input clkInC;
- 15 output clkOutA;
- 16 output clkOutB;
- 17 output clkOutC;
- 18 input clkGateA;
- 19 **input** clkGateB;
- 20 input clkGateC; 21 assign clkOutA = clkInA&clkGat
 - ign clkOutA = clkInA&clkGateA;
- 22 assign clkOutB = clkInB&clkGateB;
- 23 assign clkOutC = clkInC&clkGateC;
- 24 endmodule



Accessing individual signals from a triplicated bus ACCESSING TARG

If we want to be able to gate individual sub-signals in a triplicate clock, we have to use similar trick as in the resetBlock.





1 module clockGatingTMR(clkInA, 2 clkInB, 3 clkInC. Δ clkOutA, 5 clkOutB, 6 clkOutC, 7 clkGateA, 8 clkGateB. q clkGateC 10 11): 12 wire [2:0] clkGate; 13 input clkInA; 14 input clkInB; 15 input clkInC; 16 output clkOutA; 17 output clkOutB; 18 output clkOutC; 19 input [2:0] clkGateA; 20 input [2:0] clkGateB; 21 input [2:0] clkGateC; 22 wire gateA = clkGate[0]; 23 wire gateB = clkGate[1]; 24 wire gateC = clkGate[2]; 25 assign clkOutA = clkInA&gateA; 26 assign clkOutB = clkInB&gateB; 27 assign clkOutC = clkInC&gateC; 28 29 majorityVoter #(.WIDTH(3)) clkGateVoter (.inA(clkGateA), 30 .inB(clkGateB), 31 .inC(clkGateC), 32 33 .out(clkGate) 34); 35 endmodule

Triple Modular Redundancy Generator

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